

L Number	Hits	Search Text	DB	Time stamp
-	7	valence adj band and conduction adj band and semiconductor same testing	USOCR	2002/12/06 18:27
-	1	2790952.URPN.	USPAT	2002/12/06 18:42
-	6	3493767.URPN.	USPAT	2002/12/06 18:43
-	4	valence adj band and conduction adj band and semiconductor same testing	EPO; JPO; DERWENT; IBM_TDB	2002/12/06 18:47
-	39	valence adj band and conduction adj band and semiconductor same testing	USPAT; US-PGPUB	2002/12/06 19:25
-	8	(valence adj band and conduction adj band and semiconductor same testing) and 324/\$.cccls.	USPAT; US-PGPUB	2002/12/06 19:26
-	0	20020021141.URPN.	USPAT	2002/12/06 19:39
-	3	("4051437" "4287473" "4333051").PN.	USPAT	2002/12/06 19:40
-	14	4599558.URPN.	USPAT	2002/12/06 19:41
-	9	measuring same conduction same valence same gap same band	USOCR	2002/12/06 20:02
-	2	measuring same conduction same valence same gap same band	EPO; JPO; DERWENT; IBM_TDB	2002/12/06 20:02
-	7	measuring same conduction same valence same gap same band	USPAT; US-PGPUB	2002/12/06 20:04